Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/539,804	INOUE ET AL.	
Examiner	Art Unit	
Jay M. Patidar	2862	

	SEAR	CHED	
Class	Subclass	Date	Examiner
324	207.25	10/2/2006	JP
	173-174		
384	448		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEAR((INCLUDING SE	CH NOTES EARCH STRATE	GY)
	DATE	EXMR
EAST searched. TEXT searched.	10/2/200	96 JP
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